

Notice of References Cited	Application/Control No. 10/531,208	Applicant(s)/Patent Under Reexamination UEDA ET AL.	
	Examiner Sin J. Lee	Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-322656	11-1999	Japan	Nishikubo et al.	N/A
	O	WO 02/079131 A1	10-2002	Japan	Hanabata et al.	N/A
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chemical Abstract 1999:744383 for JP 11-322656 (Nishikubo et al).
	V	DERWENT English abstract for JP 11-322656 (Nishikubo et al).
	W	Chemical Abstract 137:302225 for WO 02/079131 A1 (Hanabata et al).
	X	Chemical Abstract 1998:475830 (Sakamizu et al).

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.